

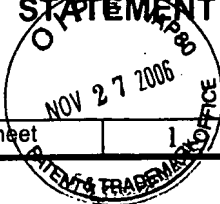
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Complete if Known

Application No.	10/668,651
Filing Date	September 23, 2003
First Named Inventor	R. Dean Adams
Art Unit	2108 2117
Examiner Name	Phung M. Chung
Attorney Docket Number	23748-09256

Sheet 1 of 3



U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document No. Number - Kind Code ² (if known)	Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
IPC/ ↑ ↓ IPC/	A1	US-2005/0257109 A1	11-17-2005	Averbuj et al.
	A2	US-6,907,554	11-11-2004	Adams et al.
	A3	US-2004/0199843 A1	10-07-2004	Hansquine et al.
	A4	US-6,795,942	09-21-2004	Schwarz
	A5	US-6,694,461	02-17-2004	Treuer
	A6	US-6,668,347	12-23-2003	Babella et al.
	A7	US-6,643,807	11-04-2003	Heaslip et al.
	A8	US-2003/0167427 A1	09-04-2003	Kraus et al.
	A9	US-6,594,788	07-15-2003	Yasui
	A10	US-2003/0120974 A1	06-26-2003	Adams et al.
	A11	US-2003/0074616 A1	04-17-2003	Dorsey
	A12	US-6,373,758	04-16-2002	Hughes et al.
	A13	US-2002/0114202 A1	08-22-2002	Adams et al.
	A14	US-6,304,989	10-16-2001	Kraus et al.
	A15	US-6,259,637	07-10-2001	Wood et al.
	A16	US-6,256,757	07-03-2001	Arkin
	A17	US-6,255,836	07-03-2001	Schwarz et al.
	A18	US-6,085,334	07-04-2000	Giles et al.
	A19	US-6,073,258	06-06-2000	Wheater
	A20	US-6,070,256	05-30-2000	Wu et al.
	A21	US-6,026,505	02-15-2000	Hederg et al.
	A22	US-5,961,653	10-05-1999	Kalter et al.
	A23	US-5,912,901	06-15-1999	Adams et al.
	A24	US-5,812,469	09-22-1998	Nadeau-Dostie et al.
	A25	US-5,796,745	08-18-1998	Adams et al.
	A26	US-5,784,323	07-21-1998	Adams et al.
	A27	US-5,764,878	06-09-1998	Kablanian et al.

Examiner Signature	/Phung Chung/	Date Considered	05/01/2007
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23748/09256/DOCS/1674509.1

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/PC/	A28	US-5,535,164	07-09-1996	Adams et al.
/PC/	A29	US-5,337,318	08-09-1994	Tsukakoshi et al.
/PC/	A30	US-5,313,424	05-17-1994	Adams et al.
/PC/	A31	US-5,173,906	12-22-1992	Dreibelbis et al.
/PC/	A32	US-4,751,656	06-14-1988	Conti et al.
/PC/	A33	US-4,603,404	07-29-1986	Yamauchi et al.
/PC/	A34	US-10/668,651	09-23-2003	Adams et al.

FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ³ – Number ⁴ Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	T ⁶
/PC/	B1	EP 1343174 A2	09-10-2003	iRoC Technologies	
/PC/	B2	EP 1343173 A1	09-10-2003	iRoC Technologies	
/PC/	B3	WO 02/065291 A2	08-22-2002	iRoC Technologies (ENGLISH ABSTRACT)	
/PC/	B4	WO 01/67463 A1	03-09-2001	Mentor Graphics Corporation	

OTHER REFERENCES – NON-PATENT LITERATURE DOCUMENTS				
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T ⁶	
/PC/	C1	AITKEN, R., "Applying Defect-Based Test to Embedded Memories in a COT Model," Proceedings IEEE Memory Technology Design and Test Workshop, 2003, pp. 1-6.		
/PC/	C2	BENSO, A. et al., "Programmable Built-In Self-Testing of Embedded RAM Clusters in System-On-Chip Architecture," Communications Magazine, IEEE, September 2003, pp. 90-97, Vol. 41, No. 9.		
/PC/	C3	BORRI, S. et al., "Defect-Oriented Dynamic Fault Models for Embedded-SRAMs," 6 pages.		
/PC/	C4	"Built-In Self-Test (BIST) Using Boundary Scan," Texas Instruments, December 1996, 21 pages.		
/PC/	C5	DEKKER, R. et al., "A Realistic Self-Test Machine for Static Random Access Memories," 1988 International Test Conference, IEEE, 1988, pp. 353-361.		

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Sheet 3 of 3

OTHER REFERENCES – NON-PATENT LITERATURE DOCUMENTS

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/PC/	C6	FANG, B.H. et al., "Power-Constrained Embedded Memory BIST Architecture," 18 th IEEE International Symposium on Defect and Fault Tolerance in VLSI Systems, 2003 Proceedings, November 3-5, 2003, pp. 451-458.	
/PC/	C7	HAMDIOUI, S. et al., "March SS: A Test for all Static Simple RAM Faults," Proceedings of the 2002 IEEE International Workshop on Memory Technology, Design and Testing (MTDT 2002), IEEE, 2002, 6 pages.	
/PC/	C8	KOIKE, H. et al., "A BIST Scheme Using Microprogram ROM for Large Capacity Memories," 1990 International Test Conference, IEEE, 1990, pp. 815-822.	
/PC/	C9	KOREN, I. et al., "Fault Tolerance in VLSI Circuits," Computer, IEEE, July 1990, pp. 73-83.	
/PC/	C10	KOSCIANSKI, M., "Built-In Self Test Insertion In A System On A Chip," ETW 2000, May 2000, Silicon & Software Systems, pp. 1-19.	
/PC/	C11	NAGURA, Y. et al., "Test Cost Reduction by At-Speed BISR for Embedded DRAMs," ITC International Test Conference, IEEE, 2001, pp. 182-187.	
/PC/	C12	POWELL, T.J. et al., "BIST for Deep Submicron ASIC Memories with High Performance Application," ITC International Test Conference, IEEE, 2003, p. 386-392.	
/PC/	C13	VAN DE GOOR, A. et al., "Industrial Evaluation of DRAM SIMM Tests," ITC International Test Conference, IEEE, 2000, pp. 426-435.	
/PC/	C14	WU, Cheng-Wen, "Memory Built-In Self-Test," National Tsing Hua University, 33 pages.	

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